

STN	Skúšanie vplyvu prostredia Časť 2-82: Skúšky Skúška Xw1: Skúšobné metódy vzniku výstupkov pre komponenty a časti používané v elektronických zostavách	STN EN IEC 60068-2-82 34 5791
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Environmental testing - Part 2-82: Tests - Test Xw1: Whisker test methods for components and parts used in electronic assemblies

Táto norma obsahuje anglickú verziu európskej normy.
This standard includes the English version of the European Standard.

Táto norma bola oznámená vo Vestníku ÚNMS SR č. 11/19

Obsahuje: EN IEC 60068-2-82:2019, IEC 60068-2-82:2019

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EN IEC 60068-2-82

NORME EUROPÉENNE

EUROPÄISCHE NORM

July 2019

ICS 19.040

Supersedes EN 60068-2-82:2007

English Version

**Environmental testing - Part 2-82: Tests - Test Xw1: Whisker test
methods for components and parts used in electronic
assemblies
(IEC 60068-2-82:2019)**

Essais d'environnement - Partie 2-82: Essais - Essai Xw1:
Méthodes de vérification des trichites pour les composants
et les pièces utilisés dans les ensembles électroniques
(IEC 60068-2-82:2019)

Umgebungseinflüsse - Teil 2-82: Prüfungen - Prüfung XW1:
Whisker-Prüfverfahren für Bauelemente und Teile in
elektronischen Baugruppen
(IEC 60068-2-82:2019)

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European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

CEN-CENELEC Management Centre: Rue de la Science 23, B-1040 Brussels

EN IEC 60068-2-82:2019 (E)**European foreword**

The text of document 91/1562/FDIS, future edition 2 of IEC 60068-2-82, prepared by IEC/TC 91 "Electronics assembly technology" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN IEC 60068-2-82:2019.

The following dates are fixed:

- latest date by which the document has to be implemented at national level by publication of an identical national standard or by endorsement (dop) 2020-03-18
- latest date by which the national standards conflicting with the document have to be withdrawn (dow) 2022-06-18

This document supersedes EN 60068-2-82:2007.

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In the official version, for Bibliography, the following notes have to be added for the standards indicated:

IEC 61191-1	NOTE	Harmonized as EN IEC 61191-1
IEC 61249-2-7	NOTE	Harmonized as EN 61249-2-7
IEC 61249-2-22	NOTE	Harmonized as EN 61249-2-22
IEC 61249-2-35	NOTE	Harmonized as EN 61249-2-35

Annex ZA (normative)

Normative references to international publications with their corresponding European publications

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE 1 Where an International Publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

NOTE 2 Up-to-date information on the latest versions of the European Standards listed in this annex is available here: www.cenelec.eu.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 60068-1	2013	Environmental testing - Part 1: General and guidance	EN 60068-1	2014
IEC 60068-2-14	2009	Environmental testing - Part 2-14: Tests - Test N: Change of temperature	EN 60068-2-14	2009
IEC 60068-2-20	-	Environmental testing - Part 2-20: Tests - Test T: Test methods for solderability and resistance to soldering heat of devices with leads	EN 60068-2-20	-
IEC 60068-2-58	-	Environmental testing - Part 2-58: Tests - Test Td: Test methods for solderability, resistance to dissolution of metallization and to soldering heat of surface mounting devices (SMD)	EN 60068-2-58	-
IEC 60068-2-67	-	Environmental testing - Part 2-67: Tests - Test Cy: Damp heat, steady state, accelerated test primarily intended for components	EN 60068-2-67	-
IEC 60068-2-78	-	Environmental testing - Part 2-78: Tests - Test Cab: Damp heat, steady state	EN 60068-2-78	-
IEC 60512-16-21	2012	Connectors for electronic equipment - Tests and measurements - Part 16-21: Mechanical tests on contacts and terminations - Test 16u: Whisker test via the application of external mechanical stresses	EN 60512-16-21	2012
IEC 61192-3	2002	Workmanship requirements for soldered electronic assemblies - Part 3: Through-hole mount assemblies	EN 61192-3	2003



IEC 60068-2-82

Edition 2.0 2019-05

INTERNATIONAL STANDARD

NORME INTERNATIONALE



**Environmental testing –
Part 2-82: Tests – Test Xw₁: Whisker test methods for components and parts
used in electronic assemblies**

**Essais d'environnement –
Partie 2-82: Essais – Essai Xw₁: Méthodes de vérification des trichites
pour les composants et les pièces utilisés dans les ensembles électroniques**



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IEC 60068-2-82

Edition 2.0 2019-05

INTERNATIONAL STANDARD

NORME INTERNATIONALE



**Environmental testing –
Part 2-82: Tests – Test Xw₁: Whisker test methods for components and parts
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**Essais d'environnement –
Partie 2-82: Essais – Essai Xw₁: Méthodes de vérification des trichites
pour les composants et les pièces utilisés dans les ensembles électroniques**

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

ENVIRONMENTAL TESTING –

Part 2-82: Tests – Test Xw₁: Whisker test methods for components and parts used in electronic assemblies

FOREWORD

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International Standard IEC 60068-2-82 has been prepared by IEC technical committee 91: Electronics assembly technology.

This second edition cancels and replaces the first edition published in 2007. This edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

- extension of the scope of the test standard from electronic to electromechanic components and press-fit pins, which are used for assembly and interconnect technology;
- significant reduction of the testing effort by a knowledge-based selection of test conditions i.e. tests not relevant for a given materials system can be omitted (see Annex D);
- harmonization with JESD 201A by omission of severities M, N for temperature cycling tests;

- highly reduced test duration (1 000 h instead of 4 000 h) for damp-heat test by introducing test condition at elevated humidity of 85 % R.H. and a temperature of 85 °C providing increased severity.

The text of this International Standard is based on the following documents:

FDIS	Report on voting
91/1562/FDIS	91/1573/RVD

Full information on the voting for the approval of this International Standard can be found in the report on voting indicated in the above table.

A list of all parts in the IEC 60068 series, published under the general title *Environmental testing*, can be found on the IEC website.

This document has been drafted in accordance with the ISO/IEC Directives, Part 2.

The committee has decided that the contents of this document will remain unchanged until the stability date indicated on the IEC website under "<http://webstore.iec.ch>" in the data related to the specific document. At this date, the document will be

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ENVIRONMENTAL TESTING –

Part 2-82: Tests – Test Xw₁: Whisker test methods for components and parts used in electronic assemblies

1 Scope

This part of IEC 60068 specifies tests for the whiskering propensity of surface finishes of electric or electronic components and mechanical parts such as punched/stamped parts (for example, jumpers, electrostatic discharge protection shields, mechanical fixations, press-fit pins and other mechanical parts used in electronic assemblies) representing the finished stage, with tin or tin-alloy finish. Changes of the physical dimensions of mould compounds, plastics and the like during the required test flow are not considered or assessed. The test methods have been developed by using a knowledge-based approach.

This document can also be used at sub-suppliers, like plating shops, stamping shops or other service providers to ensure a consistent surface quality within the supply chain.

These test methods are employed with defined acceptance criteria by a relevant component or application specification.

The tests described in this document are applicable for initial qualification, for periodic monitoring in accordance with Clause 7, and for changes of technology or manufacturing processes of existing surfaces in accordance with Clause 9.

The mating area of connectors is not covered by this test method. IEC 60512-16-21 applies for the mating areas of connectors.

2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60068-1:2013, *Environmental testing – Part 1: General and guidance*

IEC 60068-2-14:2009, *Environmental testing – Part 2-14: Tests – Test N: Change of temperature*

IEC 60068-2-20, *Environmental testing – Part 2-20: Tests – Test T: Test methods for solderability and resistance to soldering heat of devices with leads*

IEC 60068-2-58, *Environmental testing – Part 2-58: Tests – Test Td: Test methods for solderability, resistance to dissolution of metallization and to soldering heat of surface mounting devices (SMD)*

IEC 60068-2-67, *Environmental testing – Part 2-67: Tests – Test Cy: Damp heat, steady state, accelerated test primarily intended for components*

IEC 60068-2-78, *Environmental testing – Part 2-78: Tests – Test Cab: Damp heat, steady state*

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IEC 61192-3:2002, *Workmanship requirements for soldered electronic assemblies – Part 3: Through-hole mount assemblies*¹

IEC 60512-16-21:2012, *Connectors for electronic equipment – Tests and measurements – Part 16-21: Mechanical tests on contacts and terminations – Test 16u: Whisker test via the application of external mechanical stresses*

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¹ Withdrawn publication.